

Product/Process Change Notice - PCN 16_0282 Rev. -

Analog Devices, Inc. Three Technology Way Norwood, Massachusetts 02062-9106

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date. ADI contact information is listed below.

PCN Title: Addition of Analog Devices, Inc. General Trias (ADGT) as Qualified Test Site for

iSensor inertial measurement units (IMUs)

Publication Date: 09-Jan-2017

Description Of Change Add Analog Devices, Inc. General Trias site (ADGT, Cavite, Philippines) as an approved Test Site for ADiS1636X products. Detection For Change Increase test capacity. Impact of the change (positive or negative) on fit, form, function & reliability None Increase test capacity in the change (positive or negative) on fit, form, function & reliability Increase test capacity in the change (positive or negative) on fit, form, function & reliability Increase test capacity in the change (positive or negative) on fit, form, function & reliability Increase test capacity in the change (positive or negative) on fit, form, function & reliability Increase test capacity in the change (positive or negative) on fit, form, function & reliability Increase test capacity in the change (positive or negative) on fit, form, function & reliability Increase test capacity in the change (positive or negative) on fit, form, function & reliability Increase test capacity in the change (positive or negative) on fit, form, function & reliability Increase test capacity in the change (positive or negative) on fit, form, function & reliability Increase test capacity in the change (positive or negative) on fit, form, function & reliability Increase test capacity in the change (positive or negative) on fit, form, function & reliability Increase test capacity in the change (positive or negative) on fit, form, function & reliability Increase test capacity in the change (positive or negative) on fit, form, function & reliability Increase test capacity in the change (positive or negative) on fit, form, function & reliability Increase test capacity in the change (positive or negative) on fit, form, function & reliability Increase test capacity in the change (positive or negative) on fit, form, function & reliability Increase test capacity in the change (positive or negative) on fit, form, function & reliability Increase test capacity in the change (positive or negative) on fit, form, function & reliability Incr	ffectivity Date:	09-Apr-2017 (the earliest date that a customer could expect to receive changed material)	
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	Summary of Supportin	ng Information	
			. See

Supporting Documents

Attachment 1: Type: Qualification Plan ADI_PCN_16_0282_Rev_- Qual_Plan.PDF

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.						
Americas:	PCN_Americas@analog.com	Europe:	PCN_Europe@analog.com	Japan:	PCN_Japan@analog.com	
				Rest of Asia:	PCN_ROA@analog.com	

Appendix A - Affected ADI Models				
Added Parts On This Revision - Product Family / Model Number (3)				
ADIS16362 / ADIS16362BMLZ	ADIS16364 / ADIS16364BMLZ	ADIS16365 / ADIS16365BMLZ		

Appendix B - Revision History				
Rev	Publish Date	Effectivity Date	Rev Description	
Rev	09-Jan-2017	09-Apr-2017	Initial Release	

Analog Devices, Inc.

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